

<b>Notice of References Cited</b>	Application/Control No. 09/653,156	Applicant(s)/Patent Under Reexamination AGARWAL ET AL.	
	Examiner Thanh T. Nguyen	Art Unit 2813	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,222,722	04-2001	Fukuzumi et al.	361/305
X	B	US-6,780,704	08-2004	Raaijmakers et al.	438/239
X	C	US-6,551,399	04-2003	Sneh et al.	117/102
X	D	US-6,307,730	10-2001	Yamanishi, Nobuyuki	361/303
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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